

Tuesday • April 4			
Time	Regency Main		
8:00 AM	Welcome & Introduction		
8:10 AM	Introduction to Technical Program		
8:30 AM	Keynote 1		
9:15 AM	Keynote 2		
10:00 AM	Awards		
10:15 AM	Break (20min)		
	Reg Main	Reg I	Reg IV
10:35 AM	2A - WBG	2B - PI	
10:40 AM	2A.1	2B.1	
11:05 AM	2A.2	2B.2	
11:30 AM	2A.3	2B.3	
11:55 AM	2A.4	2B.4	
12:20 PM	Break (20min) - Author's Corner		
12:40 PM	Roadmap Discussion (90min)*		
2:10 PM	2D - XT	2E - SER	2F - PV
2:15 PM	2D.1	2E.1	2F.1
2:40 PM	2D.2	2E.2	2F.2
3:05 PM	2D.3	2E.3	2F.3
3:30 PM	Break (20min) - Author's Corner		
3:50 PM	2D.4	ESREF	2F.4
4:15 PM	2D.5		2F.5
4:40 PM	2D.6		
5:05 PM	Break (20min) - Author's Corner		
5:25 PM	Adjourn		

6:30 PM	Workshops (6:30-9:30PM)		
9:30 PM			

* Panel presentation and discussion with International Roadmap of Devices and Systems (IRDS)

Keynote 1: Dr. Nancy Currie-Gregg, NASA Astronaut and NESC Principal Engineer, "NASA Human Exploration Missions and Reliability Challenges"

Keynote 2: Ronald Newhart, IBM Distinguished Engineer, "System-Level Reliability Challenges with Technology Scaling"

Wednesday • April 5			
Time	Reg Main	Reg I	Reg IV
8:00 AM	3A - PR	3B - WBG	3C - FEOL
8:05 AM	3A.1	3B.1	3C.1
8:30 AM	3A.2	3B.2	3C.2
8:55 AM	3A.3	3B.3	3C.3
9:20 AM	3A.4	3B.4	3C.4
9:45 AM	3A.5	3B.5	3C.5
10:10 AM	Break (30min) - Author's Corner		
10:40 AM	3D - SER	3E - RT	3F - ESD
10:45 AM	3D.1	3E.1	3F.1
11:10 AM	3D.2	3E.2	3F.2
11:35 AM	3D.3	3E.3	3F.3
12:00 PM	3D.4	3E.4	
12:25 PM	Break (20min) - Author's Corner		
12:45 PM	Lunch (90min)		
2:15 PM	4A - 3D	4B - WBG	4C - CR
2:20 PM	4A.1	4B.1	4C.1
2:45 PM	4A.2	4B.2	4C.2
3:10 PM	4A.3	4B.3	4C.3
3:35 PM	Break (30min) - Author's Corner		
4:05 PM	4A.4	4B.4	4C.4
4:30 PM	4A.5	4B.5	4C.5
4:55 PM	4A.6		4C.6
5:20 PM	Break (20min) - Author's Corner		
5:40 PM	Adjourn		

6:30 PM	Poster Session (6:30-9:30PM)		
9:30 PM			

3D 2.5D / 3D / Packaging
 BEOL Back-End Dielectrics
 CR Circuit Aging / Reliability
 ESD Electrostatic Discharge
 FA Failure Analysis
 FEOL Front-End Dielectrics
 MET Metallization Reliability
 MY Memory Reliability
 PI Process Integration

PR Product Reliability
 PV Photovoltaics
 RT Reliability Testing
 SER Soft Errors
 SYS System Reliability
 WBG Wide Band Gap
 XT Transistor Reliability
 XT/BC Transistors - Beyond CMOS

Thursday • April 6			
Time	Reg Main	Reg I	Reg IV
8:00 AM	5A - MY	5B - BEOL	5C - FA
8:05 AM	5A.1	5B.1	5C.1
8:30 AM	5A.2	5B.2	5C.2
8:55 AM	5A.3	5B.3	5C.3
9:20 AM	5A.4	5B.4	5C.4
9:45 AM	5A.5	5B.5	5C.5
10:10 AM	Break (30min) - Author's Corner		
10:40 AM	6A - XT/BC	6B - MET	6C - SYS
10:45 AM	6A.1	6B.1	6C.1
11:10 AM	6A.2	6B.2	6C.2
11:35 AM	6A.3	6B.3	6C.3
12:00 PM	Break (20min) - Author's Corner		
12:20 PM	Lunch (90min)		
1:50 PM	6A.4	6B.4	6C.4
2:15 PM	6A.5	6B.5	6C.5
2:40 PM	6A.6	6B.6	6C.6
3:05 PM		6B.7	
3:30 PM	Break (20min) - Author's Corner		
3:50 PM	Closing and 2018 Introduction		
4:15 PM	Adjourn		